MOSFET

Metal Oxide Semiconductor Field Effect Transistor

OptiMOS™ Power-Transistor, 120V

OptiMOS™ 3 Power-Transistor
IPD_S110N12N3 G

Data Sheet

Rev. 2.4
Final

Industrial & Multimarket

OptiMOS™3Power-Transistor

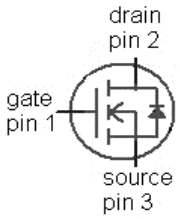
Product Summary

V_{DS}	120	V
$R_{DS(on),max}$	11	mΩ
I_D	75	A

Features

- N-channel, normal level
- Excellent gate charge x $R_{DS(on)}$ product (FOM)
- Very low on-resistance $R_{DS(on)}$
- 175 °C operating temperature
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC[1)] for target application
- Halogen free according to IEC61249-2-21 *
- Ideal for high-frequency switching and synchronous rectification

Type	IPS110N12N3 G	IPD110N12N3 G
Package	PG-TO251-3	PG-TO252-3
Marking	110N12N	110N12N



Maximum ratings, at T_j=25 °C, unless otherwise specified

Parameter	**Symbol**	**Conditions**	**Value**	**Unit**
Continuous drain current	I_D	T_C=25 °C	75	A
		T_C=100 °C	54	
Pulsed drain current[2)]	$I_{D,pulse}$	T_C=25 °C	300	
Avalanche energy, single pulse	E_{AS}	I_D=75 A, R_{GS}=25 Ω	120	mJ
Gate source voltage[3)]	V_{GS}		±20	V
	P_{tot}	T_C=25 °C	136	W
Operating and storage temperature	T_j, T_{stg}		-55 ... 175	°C
IEC climatic category; DIN IEC 68-1			55/175/56	

[1)] J-STD20 and JESD22

[2)] see figure 3

[3)] T_{jmax}=150°C and duty cycle D=0.01 for V_{gs}<-5V

* Except package TO251-3

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - case	R_{thJC}		-	-	1.1	K/W
Thermal resistance, junction - ambient	R_{thJA}	minimal footprint	-	-	75	
		6 cm^2 cooling area[4)]	-	-	50	
Electrical characteristics, at T_j=25 °C, unless otherwise specified						
Static characteristics						
Drain-source breakdown voltage	$V_{(BR)DSS}$	V_{GS}=0 V, I_D=1 mA	120	-	-	V
Gate threshold voltage	$V_{GS(th)}$	V_{DS}=V_{GS}, I_D=83 µA	2	3	4	
Zero gate voltage drain current	I_{DSS}	V_{DS}=100 V, V_{GS}=0 V, T_j=25 °C	-	0.1	1	µA
		V_{DS}=100 V, V_{GS}=0 V, T_j=125 °C	-	10	100	
Gate-source leakage current	I_{GSS}	V_{GS}=20 V, V_{DS}=0 V	-	1	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	V_{GS}=10 V, I_D=75 A	-	9.2	11	mΩ
Gate resistance	R_G		-	1.5	-	Ω
Transconductance	g_{fs}	$\|V_{DS}\|>2\|I_D\|R_{DS(on)max}$, I_D=75 A	42	83	-	S

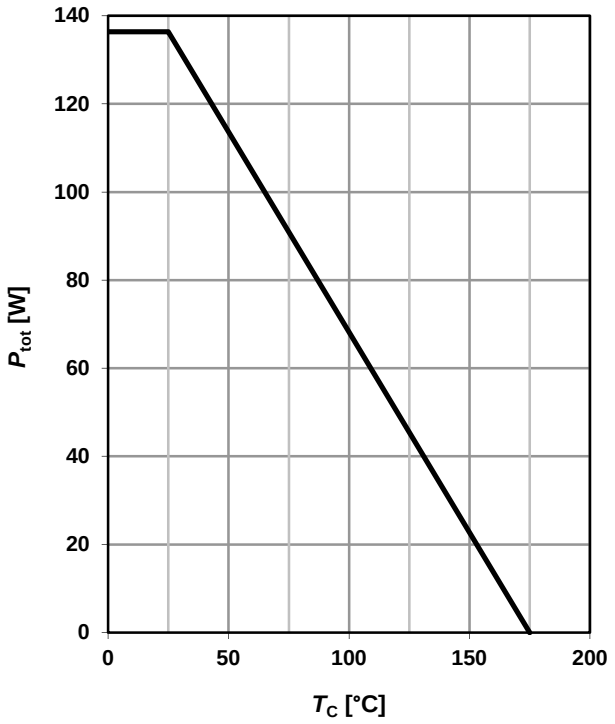
[4)] Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm^2 (one layer, 70 µm thick) copper area for drain connection. PCB is vertical in still air.

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Dynamic characteristics[6]						
Input capacitance	C_{iss}	V_{GS}=0 V, V_{DS}=60 V, f=1 MHz	-	3240	4310	pF
Output capacitance	C_{oss}		-	408	543	
Reverse transfer capacitance	C_{rss}		-	22	-	
Turn-on delay time	$t_{d(on)}$	V_{DD}=60 V, V_{GS}=10 V, I_D=75 A, $R_{G,ext}$=1.6 Ω	-	16	-	ns
Rise time	t_r		-	16	-	
Turn-off delay time	$t_{d(off)}$		-	24	-	
Fall time	t_f		-	8	-	
Gate Charge Characteristics[5]						
Gate to source charge	Q_{gs}	V_{DD}=60 V, I_D=75 A, V_{GS}=0 to 10 V	-	18	-	nC
Gate to drain charge	Q_{gd}		-	12	-	
Switching charge	Q_{sw}		-	20	-	
Gate charge total[6]	Q_g		-	49	65	
Gate plateau voltage	$V_{plateau}$		-	5.6	-	V
Output charge[6]	Q_{oss}	V_{DD}=60 V, V_{GS}=0 V	-	56	75	nC
Reverse Diode						
Diode continous forward current	I_S	T_C=25 °C	-	-	75	A
Diode pulse current	$I_{S,pulse}$		-	-	300	
Diode forward voltage	V_{SD}	V_{GS}=0 V, I_F=75 A, T_j=25 °C	-	1	1.2	V
	t_{rr}	V_R=60 V, I_F=I_S, di_F/dt=100 A/µs	-	90		ns
Reverse recovery charge	Q_{rr}		-	249		nC

[5] See figure 16 for gate charge parameter definition
[6] Defined by design. Not subject to production test

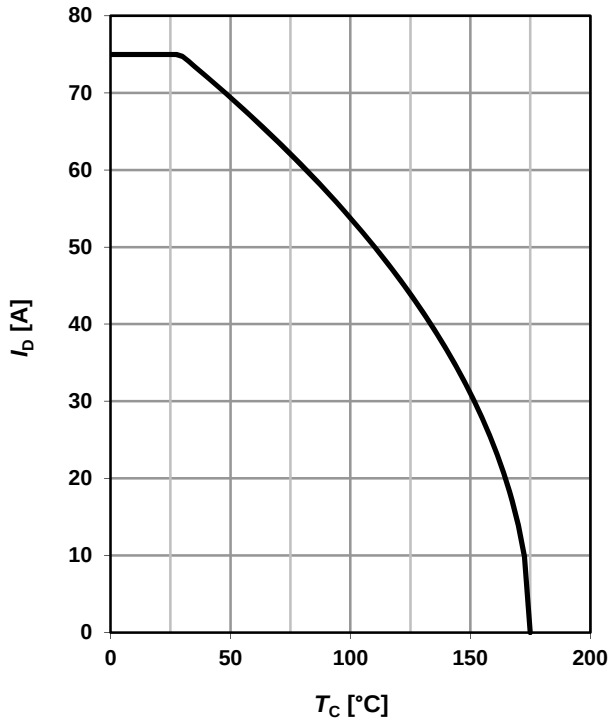
1 Power dissipation

P_{tot}=f(T_C)



2 Drain current

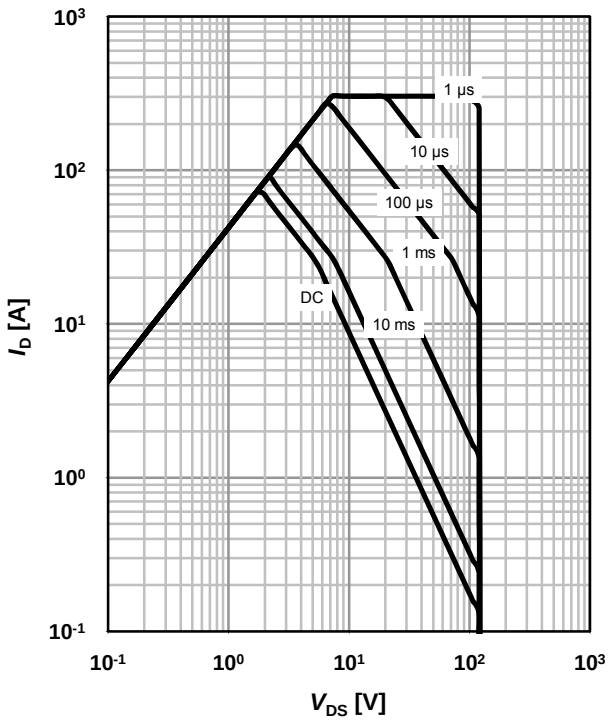
I_D=f(T_C); V_{GS}≥10 V



3 Safe operating area

I_D=f(V_{DS}); T_C=25 °C; D=0

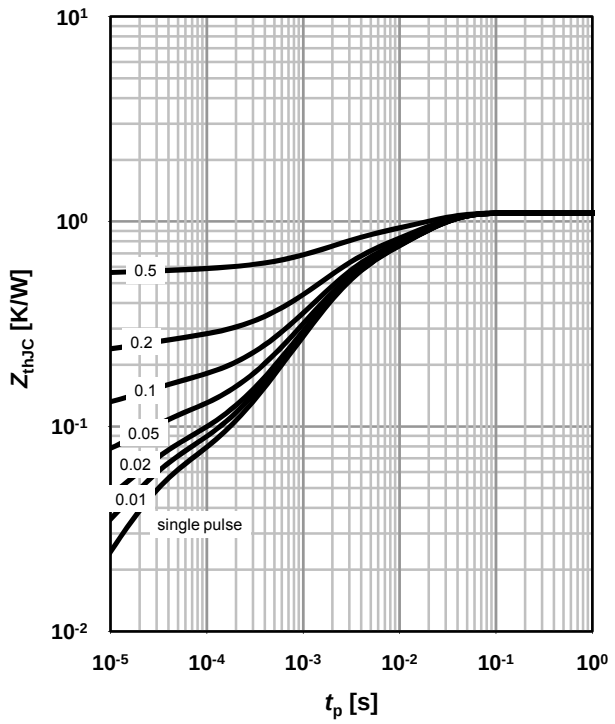
parameter: t_p



4 Max. transient thermal impedance

Z_{thJC}=f(t_p)

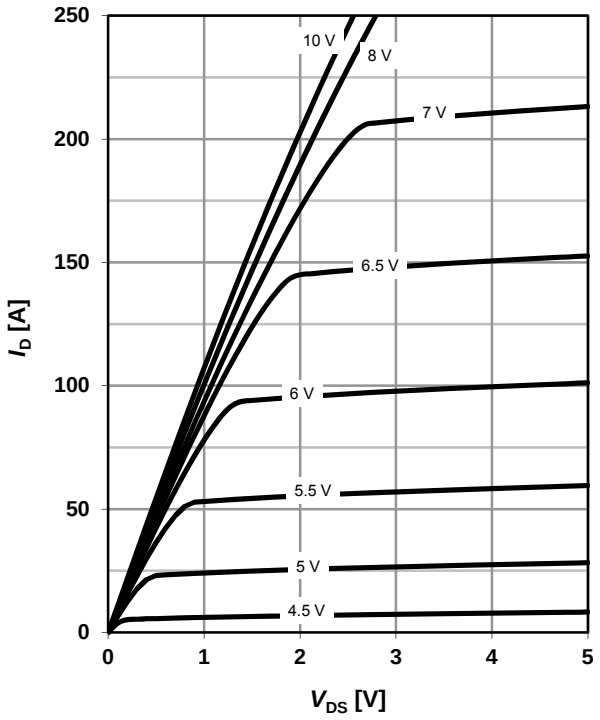
parameter: D=t_p/T



5 Typ. output characteristics

I_D=f(V_{DS}); T_j=25 °C

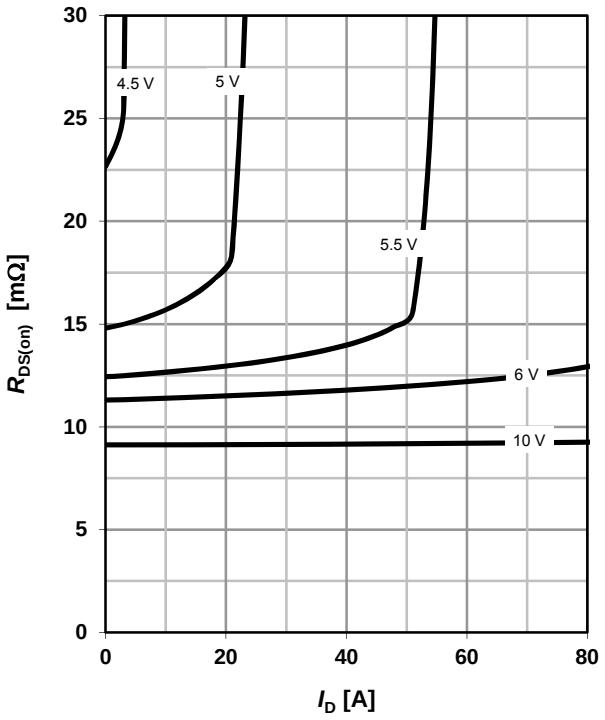
parameter: V_{GS}



6 Typ. drain-source on resistance

$R_{DS(on)}$=f(I_D); T_j=25 °C

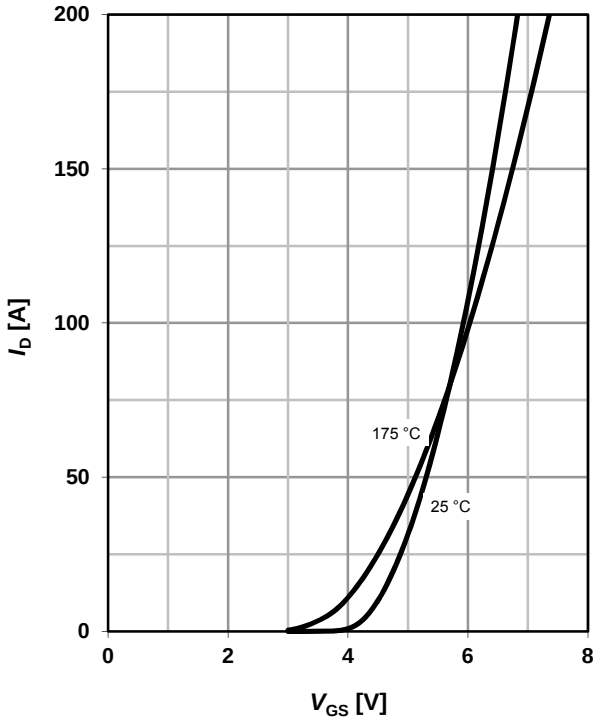
parameter: V_{GS}



7 Typ. transfer characteristics

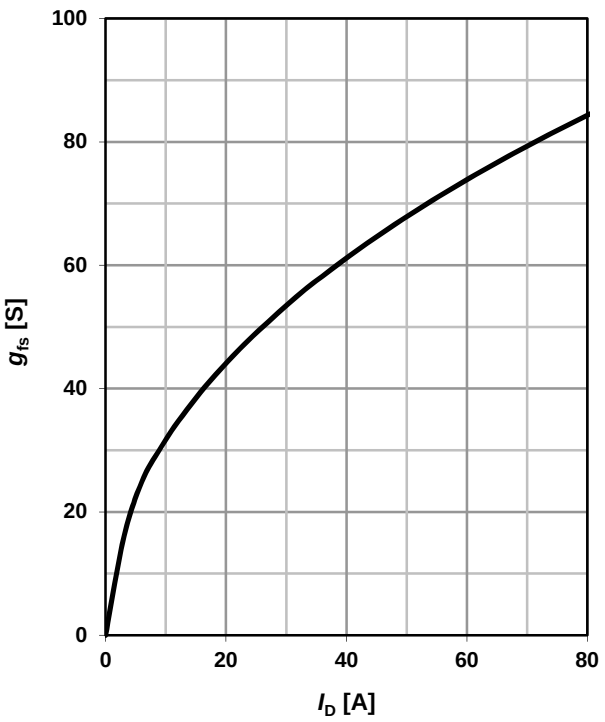
I_D=f(V_{GS}); |V_{DS}|>2|I_D|$R_{DS(on)max}$

parameter: T_j



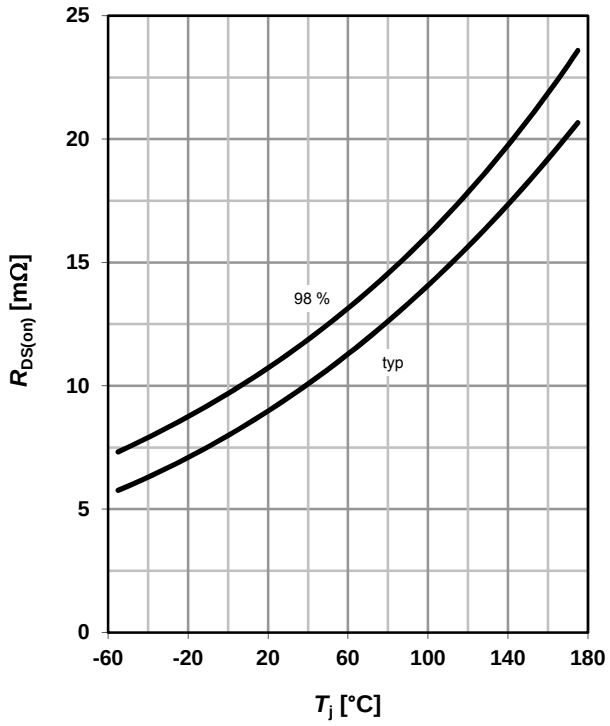
8 Typ. forward transconductance

g_{fs}=f(I_D); T_j=25 °C



9 Drain-source on-state resistance

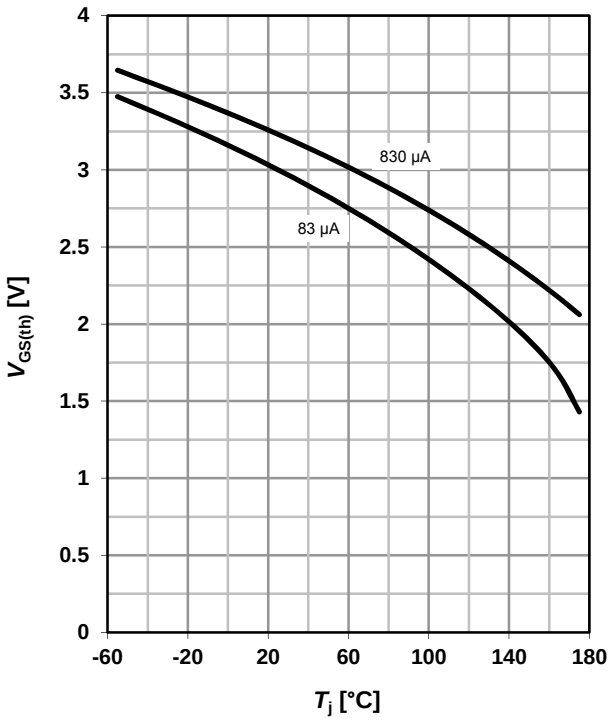
$R_{DS(on)}$=f(T_j); I_D=75 A; V_{GS}=10 V



10 Typ. gate threshold voltage

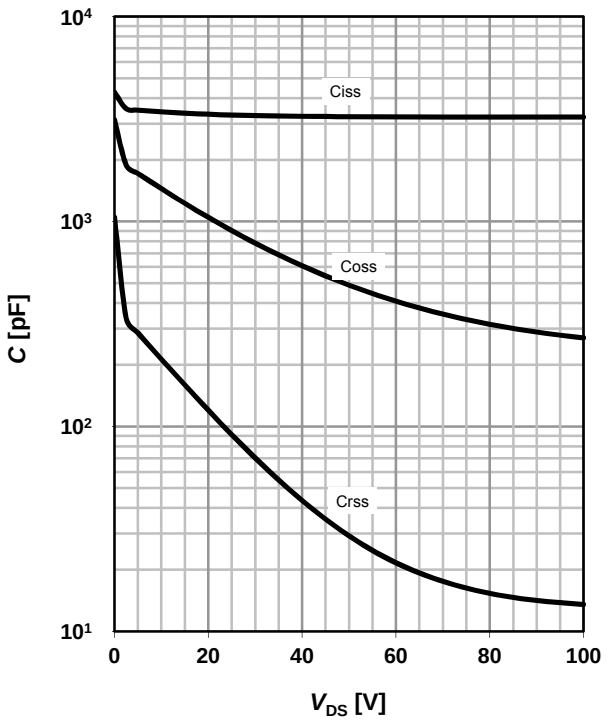
$V_{GS(th)}$=f(T_j); V_{GS}=V_{DS}

parameter: I_D



11 Typ. capacitances

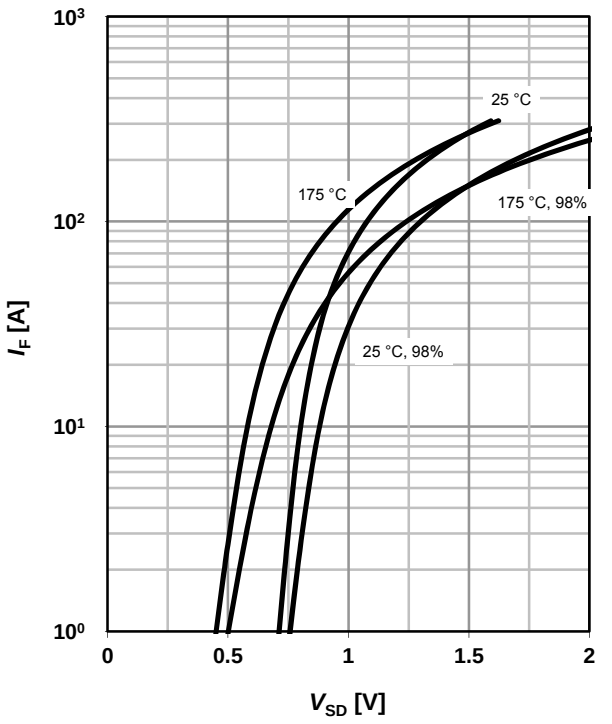
C=f(V_{DS}); V_{GS}=0 V; f=1 MHz



12 Forward characteristics of reverse diode

I_F=f(V_{SD})

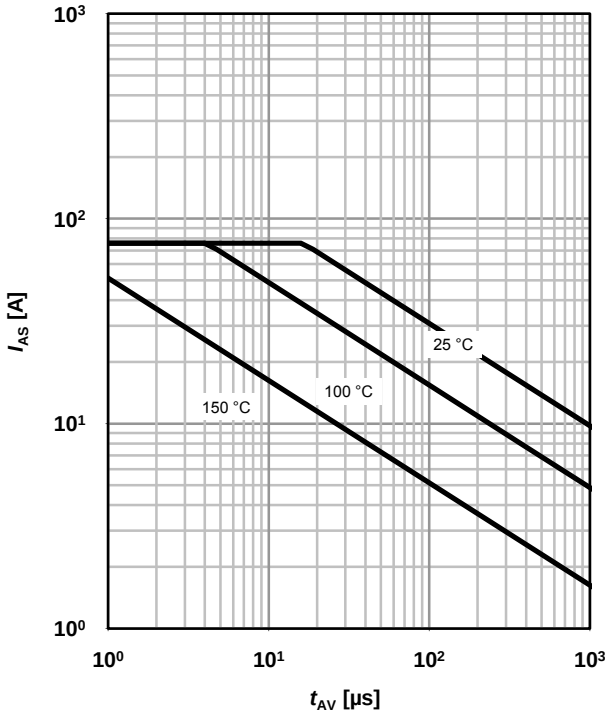
parameter: T_j



13 Avalanche characteristics

I_{AS}=f(t_{AV}); R_{GS}=25 Ω

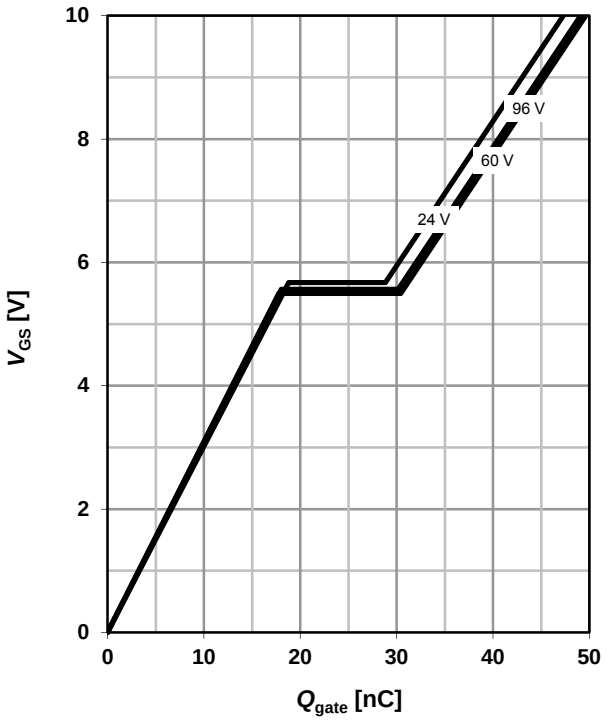
parameter: $T_{j(start)}$



14 Typ. gate charge

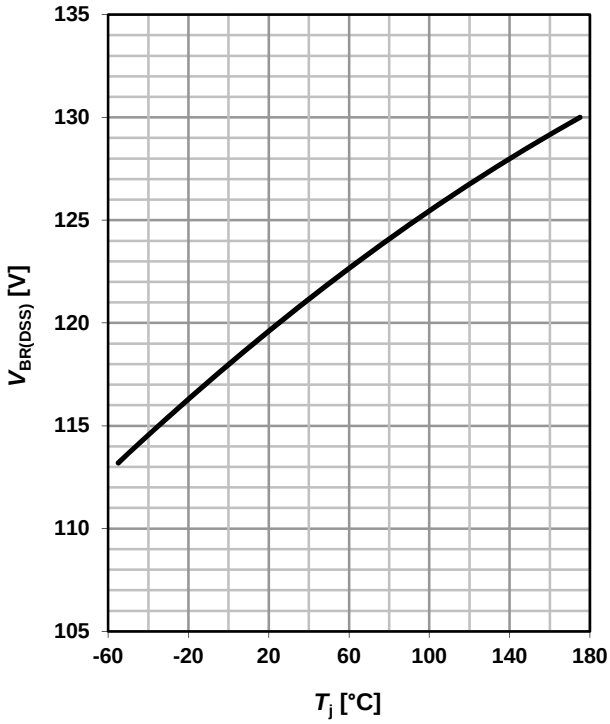
V_{GS}=f(Q_{gate}); I_D=67 A pulsed

parameter: V_{DD}

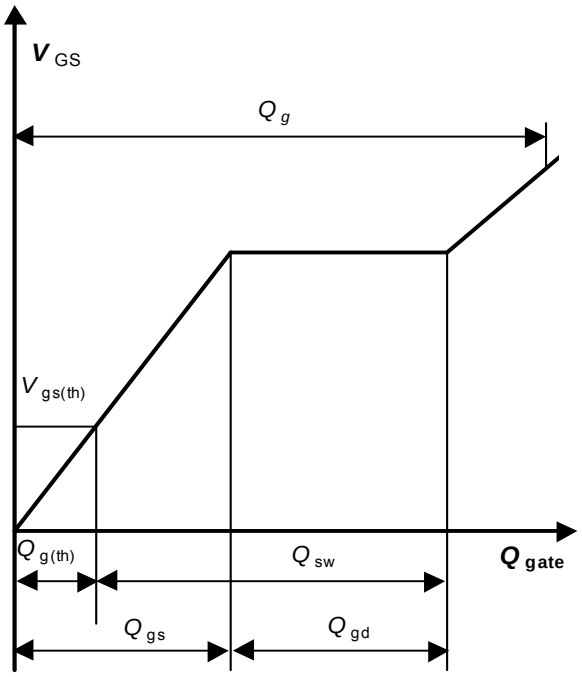


15 Drain-source breakdown voltage

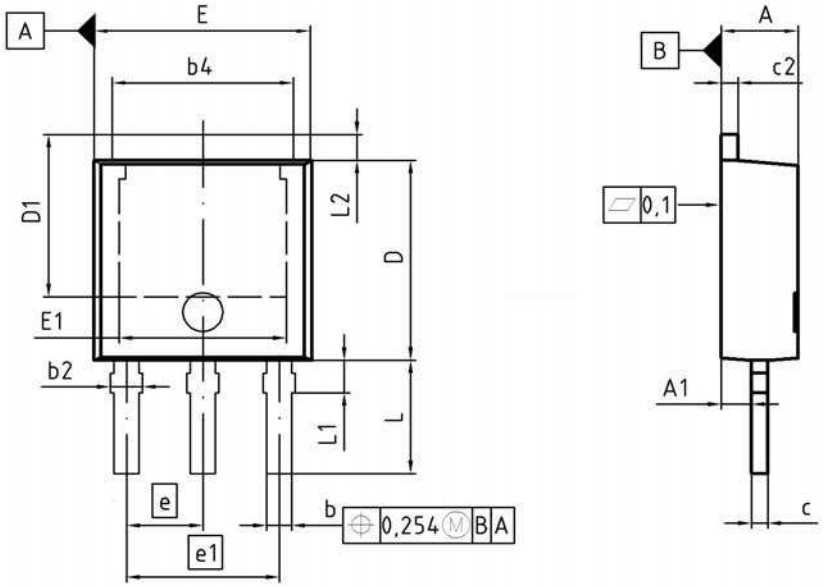
$V_{BR(DSS)}$=f(T_j); I_D=1 mA



16 Gate charge waveforms



PG-TO-251SL : Outline



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	2.18	2.39	0.086	0.094
A1	0.80	1.14	0.031	0.045
b	0.64	0.89	0.025	0.035
b2	0.65	1.15	0.026	0.045
b4	4.95	5.50	0.195	0.217
c	0.46	0.58	0.018	0.023
c2	0.46	0.89	0.018	0.035
D	5.97	6.22	0.235	0.245
D1	5.04	5.44	0.198	0.214
E	6.35	6.73	0.250	0.265
E1	4.90	5.10	0.193	0.201
e	2.29		0.090	
e1	4.57		0.180	
N	3		3	
L	3.40	3.60	0.134	0.142
L1	0.90	1.10	0.035	0.043
L2	0.90	1.10	0.035	0.043

DOCUMENT NO.
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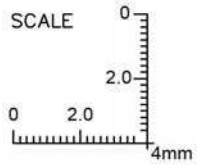
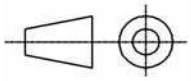
SCALE



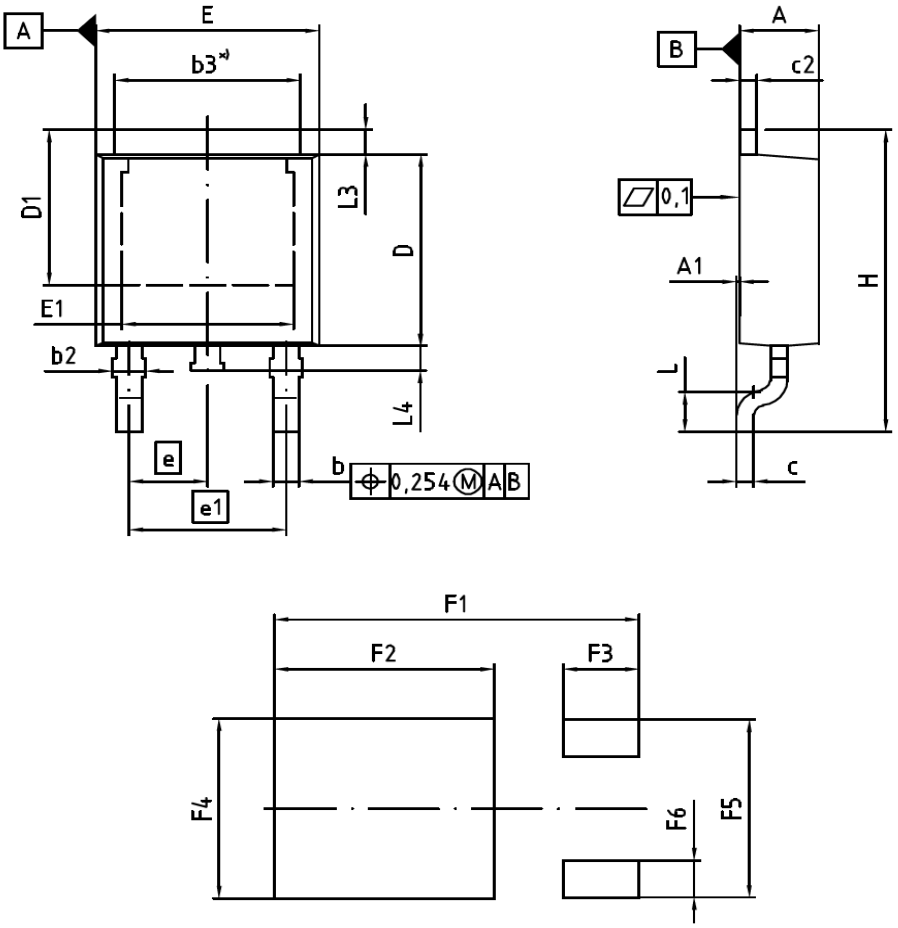
EUROPEAN PROJECTION



ISSUE DATE
17-01-2008

REVISION
03

PG-TO252-3: Outline



*) mold flash not included

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	2.16	2.41	0.085	0.095
A1	0.00	0.15	0.000	0.006
b	0.64	0.89	0.025	0.035
b2	0.65	1.15	0.026	0.045
b3	5.00	5.50	0.197	0.217
c	0.46	0.60	0.018	0.024
c2	0.46	0.98	0.018	0.039
D	5.97	6.22	0.235	0.245
D1	5.02	5.84	0.198	0.230
E	6.40	6.73	0.252	0.265
E1	4.70	5.21	0.185	0.205
e	2.29 (BSC)		0.090 (BSC)	
e1	4.57		0.180	
N	3		3	
H	9.40	10.48	0.370	0.413
L	1.18	1.70	0.046	0.067
L3	0.90	1.25	0.035	0.049
L4	0.51	1.00	0.020	0.039
F1	10.60		0.417	
F2	6.40		0.252	
F3	2.20		0.087	
F4	5.80		0.228	
F5	5.76		0.227	
F6	1.20		0.047	

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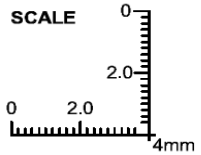
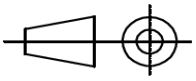


EUROPEAN PROJECTION



ISSUE DATE
16-02-2011

REVISION
04

Revision History

IPD_S110N12N3 G

Revision: 2015-07-16, Rev. 2.4

Previous Revision		
Revision	Date	Subjects (major changes since last revision)
2.4	2015-07-16	Update VGS(th) and package outline TO252-3

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